

<b>Notice of References Cited</b>	Application/Control No. 09/846,058	Applicant(s)/Patent Under Reexamination BASS ET AL.	
	Examiner Jon D Epperson	Art Unit 1639	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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	C	US-			
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	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Liu, G.-Y.; Xu, S.; Qian, Y. "Nanofabrication of Self-Assembled Monolayers Using Scanning Probe Lithography" Acc. Chem. Res. 2000, 33, 457-466
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.